ALPHA & OMEGA SEMICONDUCTOR, INC.

June 2003

AO4912
Asymmetric Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

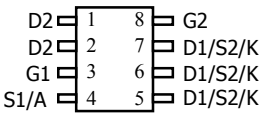
The AO4912 uses advanced trench technology to provide excellent $R_{DS(ON)}$ and low gate charge. The two MOSFETs make a compact and efficient switch and synchronous rectifier combination for use in DC-DC converters. A Schottky diode is co-packaged in parallel with the synchronous MOSFET to boost efficiency further.

Features

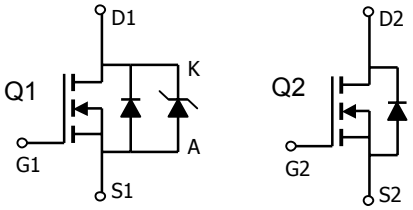
Q1	Q2	
V_{DS} (V) = 30V	V_{DS}(V) = 30V	
I_D = 8.5A	I_D=7A	
$R_{DS(ON)}$ < 17mΩ	<26mΩ	(V_{GS} = 10V)
$R_{DS(ON)}$ < 25mΩ	<31mΩ	(V_{GS} = 4.5V)

SCHOTTKY

V_{DS} (V) = 30V, I_F = 3A, V_F<0.5V@1A



SOIC-8



Absolute Maximum Ratings T_A=25°C unless otherwise noted

Parameter		Symbol	Max Q1	Max Q2	Units
Drain-Source Voltage		V_{DS}	30	30	V
Gate-Source Voltage		V_{GS}	±20	±12	V
Continuous Drain Current [A]	T_A=25°C	I_D	8.5	7	A
	T_A=70°C		6.8	6.4	
Pulsed Drain Current [B]		I_{DM}	40	30	
Power Dissipation	T_A=25°C	P_D	2	2	W
	T_A=70°C		1.28	1.28	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	-55 to 150	°C

Parameter		Symbol	Maximum Schottky	Units
Reverse Voltage		V_{DS}	30	V
Continuous Forward Current [A]	T_A=25°C	I_F	3	A
	T_A=70°C		2.2	
Pulsed Forward Current [B]		I_{FM}	20	
Power Dissipation [A]	T_A=25°C	P_D	2	W
	T_A=70°C		1.28	
Junction and Storage Temperature Range		T_J, T_{STG}	-55 to 150	°C

Parameter: Thermal Characteristics MOSFET Q1		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	48	62.5	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		74	110	
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JL}$	35	40	

Parameter: Thermal Characteristics MOSFET Q2		Symbol	Typ	Max	Units
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	48	62.5	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		74	110	
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JL}$	35	40	

Thermal Characteristics Schottky					
Maximum Junction-to-Ambient [A]	t ≤ 10s	$R_{\theta JA}$	47.5	62.5	°C/W
Maximum Junction-to-Ambient [A]	Steady-State		71	110	
Maximum Junction-to-Lead [C]	Steady-State	$R_{\theta JL}$	32	40	

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in ^{2} FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6 are obtained using 80 μs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in ^{2} FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

Q1 Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250µA, V_{GS}=0V	30			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=24V, V_{GS}=0V			1	µA
		T_J=55°C			5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±20V			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	1	1.8	3	V
$I_{D(ON)}$	On state drain current	V_{GS}=4.5V, V_{DS}=5V	30			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=8.5A		13.8	17	mΩ
		T_J=125°C		20	24	
		V_{GS}=4.5V, I_D=7.0A		19.7	25	mΩ
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=8.5A		23		S
V_{SD}	Diode+Schottky Forward Voltage	I_S=1A		0.45	0.5	V
I_S	Maximum Body-Diode+Schottky Continuous Current				3	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=15V, f=1MHz		1040		pF
C_{oss}	Output Capacitance			180		pF
C_{rss}	Reverse Transfer Capacitance			110		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz		0.7		Ω
SWITCHING PARAMETERS						
Q_g(10V)	Total Gate Charge	V_{GS}=10V, V_{DS}=15V, I_D=8.5A		19.2		nC
Q_g	Total Gate Charge			9.36		nC
Q_{gs}	Gate Source Charge			2.6		nC
Q_{gd}	Gate Drain Charge			4.2		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=15V, R_L=1.8Ω, R_{GEN}=6Ω		5.2		ns
t_r	Turn-On Rise Time			4.4		ns
$t_{D(off)}$	Turn-Off DelayTime			17.3		ns
t_f	Turn-Off Fall Time			3.3		ns
t_{rr}	Body Diode Reverse Recovery time	I_F=8.5A, dI/dt=100A/µs		16.7		ns
Q_{rr}	Body Diode Reverse Recovery charge	I_F=8.5A, dI/dt=100A/µs		6.7		nC
SCHOTTKY PARAMETERS						
I_{rm}	Maximum reverse leakage current	V_R=30V		0.007	0.05	mA
		V_R=30V, T_J=125°C		3.2	10	
		V_R=30V, T_J=150°C		12	20	
C_T	Junction Capacitance Schottky only	V_R=15V		37		pF

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A =25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the t≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in^2 FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

Q2 Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
STATIC PARAMETERS						
BV_{DSS}	Drain-Source Breakdown Voltage	I_D=250µA, V_{GS}=0V	30			V
I_{DSS}	Zero Gate Voltage Drain Current	V_{DS}=24V, V_{GS}=0V			1	µA
		T_J=55°C			5	
I_{GSS}	Gate-Body leakage current	V_{DS}=0V, V_{GS}= ±12V			100	nA
$V_{GS(th)}$	Gate Threshold Voltage	V_{DS}=V_{GS} I_D=250µA	1	1.5	2	V
$I_{D(ON)}$	On state drain current	V_{GS}=4.5V, V_{DS}=5V	25			A
$R_{DS(ON)}$	Static Drain-Source On-Resistance	V_{GS}=10V, I_D=7.0A		20	26	mΩ
		T_J=125°C		31.6	38	
		V_{GS}=4.5V, I_D=6.0A		24.3	31	mΩ
g_{FS}	Forward Transconductance	V_{DS}=5V, I_D=7A		22		S
V_{SD}	Diode Forward Voltage	I_S=1A		0.78	1	V
I_S	Maximum Body-Diode Continuous Current				3	A
DYNAMIC PARAMETERS						
C_{iss}	Input Capacitance	V_{GS}=0V, V_{DS}=15V, f=1MHz		590		pF
C_{oss}	Output Capacitance			162		pF
C_{rss}	Reverse Transfer Capacitance			40		pF
R_g	Gate resistance	V_{GS}=0V, V_{DS}=0V, f=1MHz		0.45		Ω
SWITCHING PARAMETERS						
Q_g	Total Gate Charge	V_{GS}=4.5V, V_{DS}=15V, I_D=7.0A		6.04		nC
Q_{gs}	Gate Source Charge			1.46		nC
Q_{gd}	Gate Drain Charge			2.56		nC
$t_{D(on)}$	Turn-On DelayTime	V_{GS}=10V, V_{DS}=15V, R_L=2.2Ω, R_{GEN}=6Ω		3.7		ns
t_r	Turn-On Rise Time			3.5		ns
$t_{D(off)}$	Turn-Off DelayTime			14.9		ns
t_f	Turn-Off Fall Time			2.5		ns
t_{rr}	Body Diode Reverse Recovery time	I_F=7A, dI/dt=100A/µs		21.2		ns
Q_{rr}	Body Diode Reverse Recovery charge	I_F=7A, dI/dt=100A/µs		14.2		nC

A: The value of $R_{\theta JA}$ is measured with the device mounted on 1in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The value in any a given application depends on the user's specific board design. The current rating is based on the ≤ 10s thermal resistance rating.

B: Repetitive rating, pulse width limited by junction temperature.

C. The $R_{\theta JA}$ is the sum of the thermal impedence from junction to lead $R_{\theta JL}$ and lead to ambient.

D. The static characteristics in Figures 1 to 6,12,14 are obtained using 80µs pulses, duty cycle 0.5% max.

E. These tests are performed with the device mounted on 1 in² FR-4 board with 2oz. Copper, in a still air environment with T_A=25°C. The SOA curve provides a single pulse rating.

Q1 TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

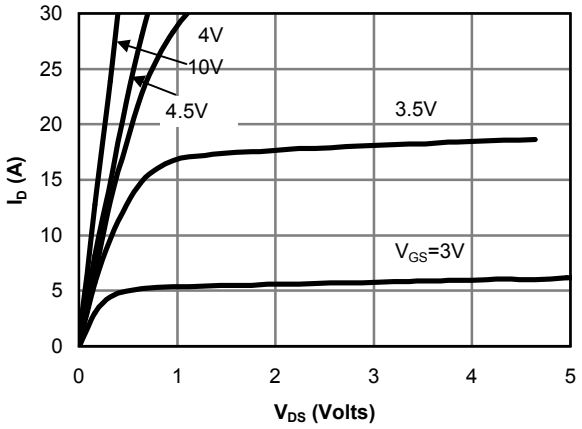


Fig 1: On-Region Characteristics

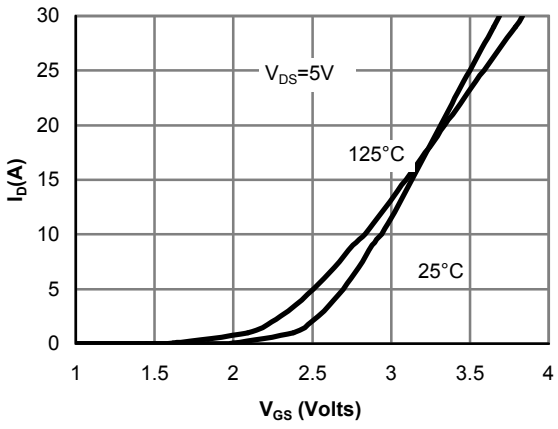


Figure 2: Transfer Characteristics

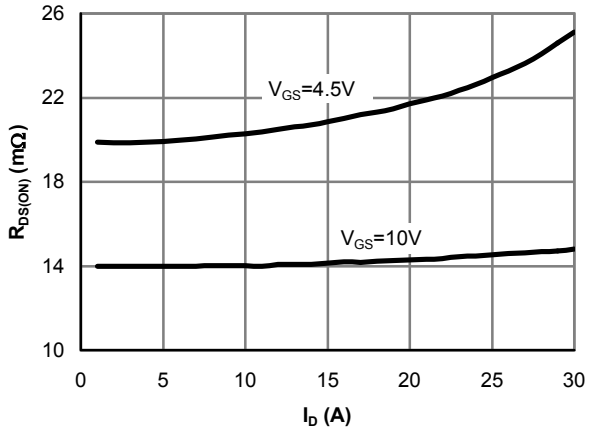


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

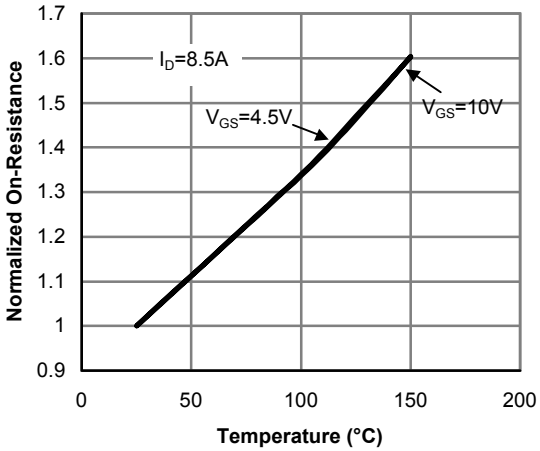


Figure 4: On resistance vs. Junction Temperature

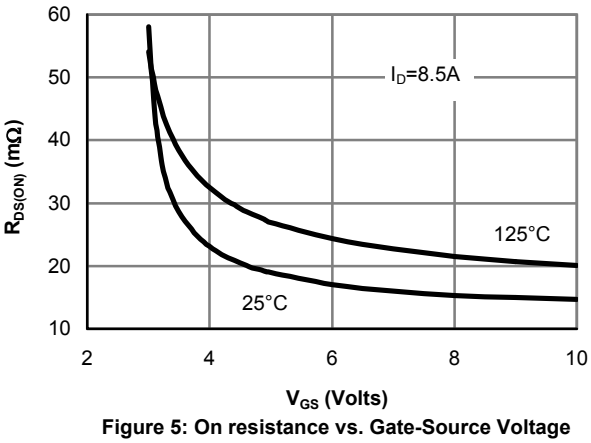


Figure 5: On resistance vs. Gate-Source Voltage

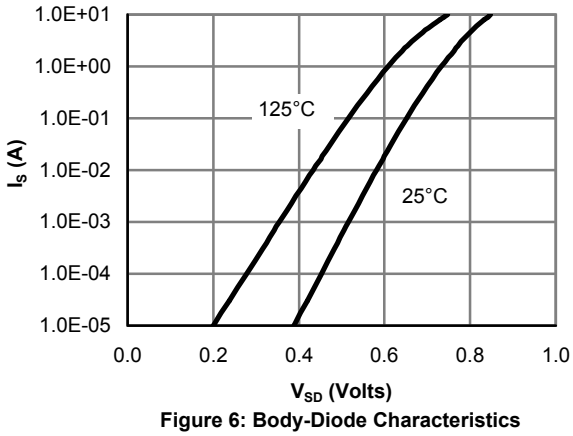


Figure 6: Body-Diode Characteristics

Q1 TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

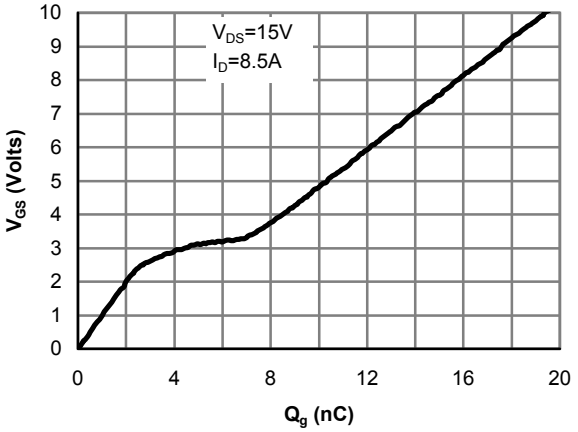


Figure 7: Gate-Charge Characteristics

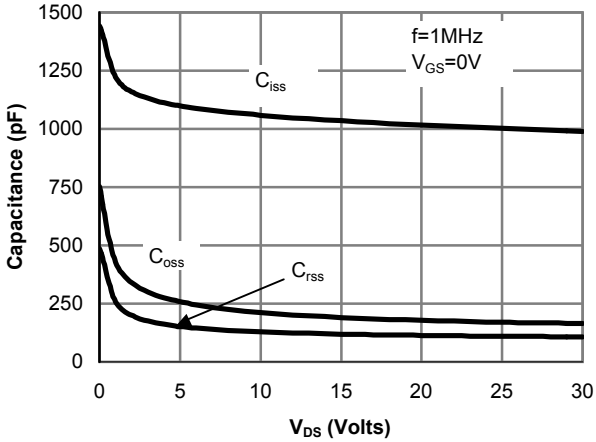


Figure 8: Capacitance Characteristics

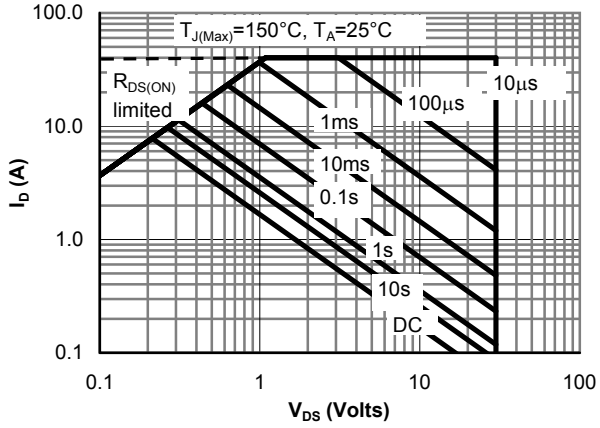


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

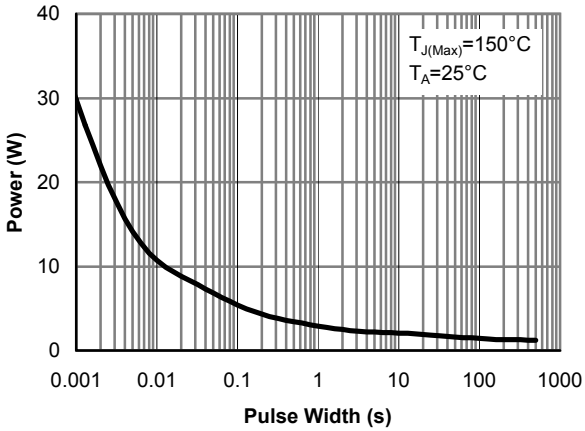


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

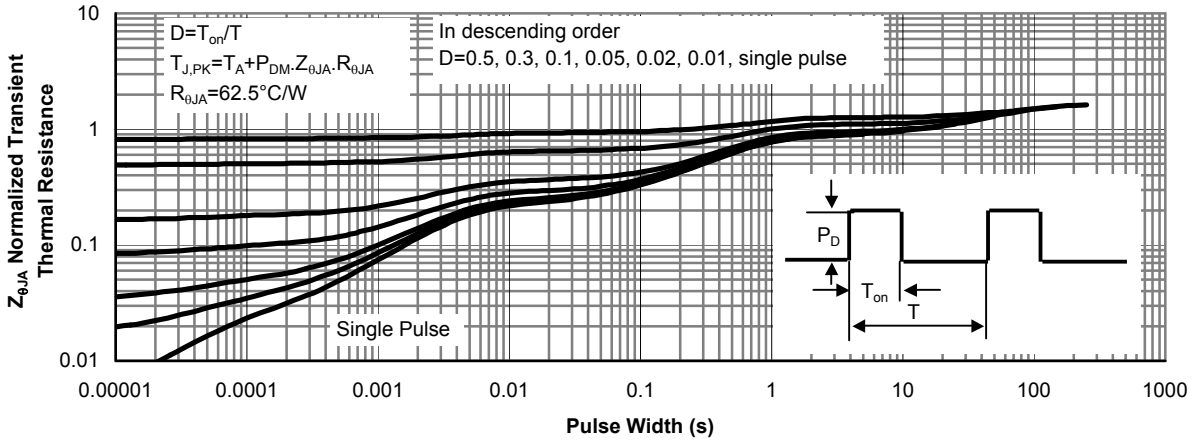


Figure 11: Normalized Maximum Transient Thermal Impedance

Q2 TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

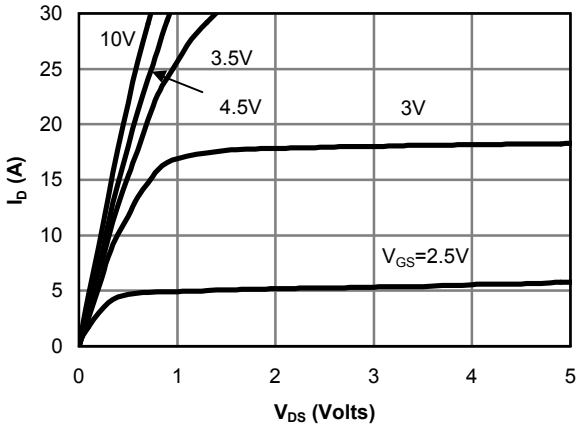


Fig 1: On-Region Characteristics

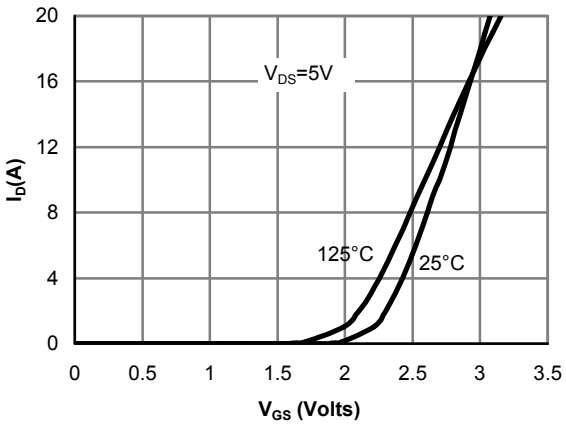


Figure 2: Transfer Characteristics

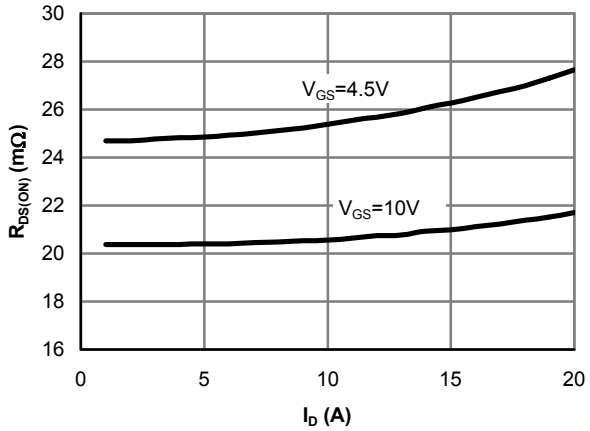


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

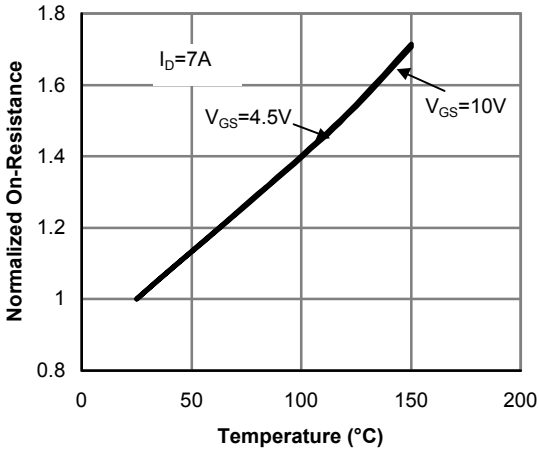


Figure 4: On resistance vs. Junction Temperature

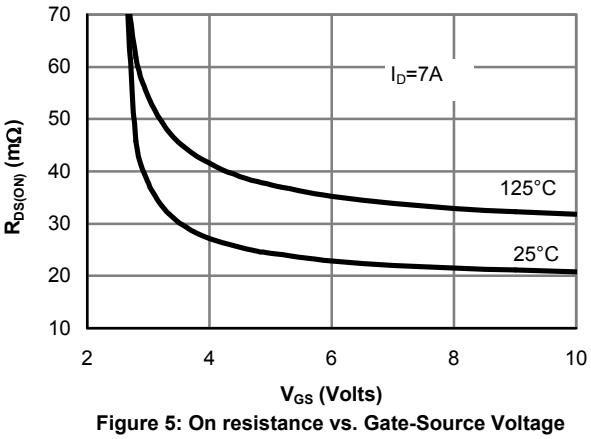


Figure 5: On resistance vs. Gate-Source Voltage

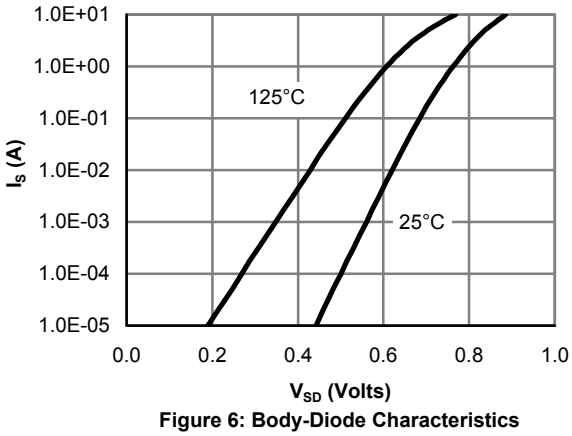


Figure 6: Body-Diode Characteristics

Q2 TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

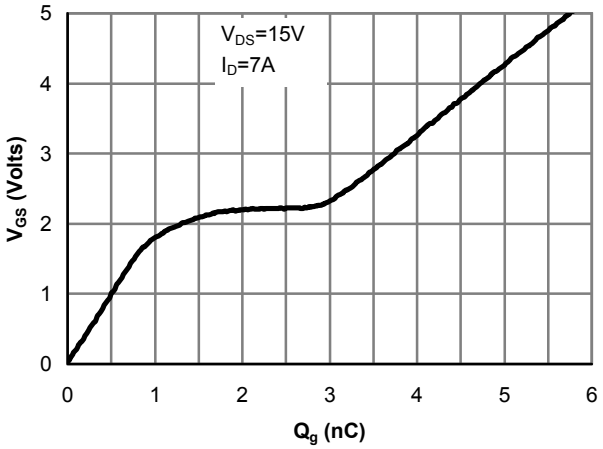


Figure 7: Gate-Charge Characteristics

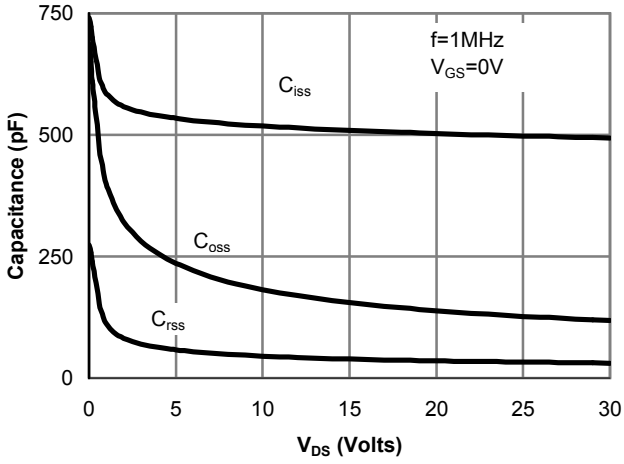


Figure 8: Capacitance Characteristics

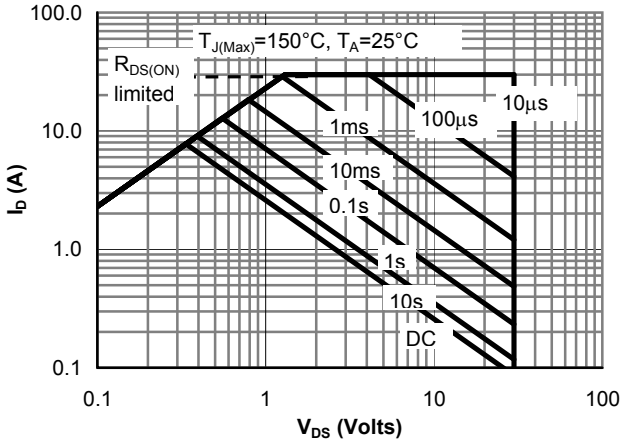


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

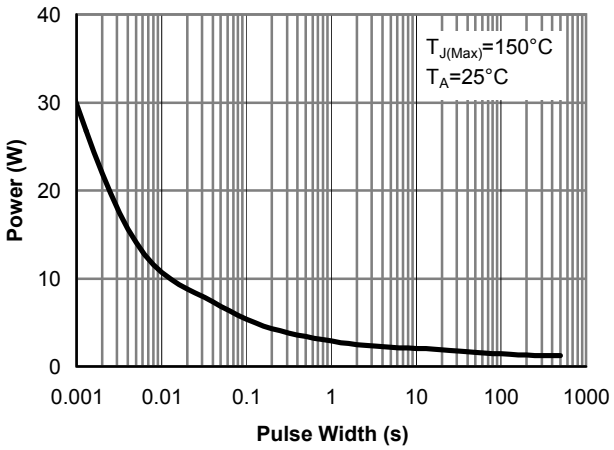


Figure 10: Single Pulse Power Rating Junction-to-Ambient (Note E)

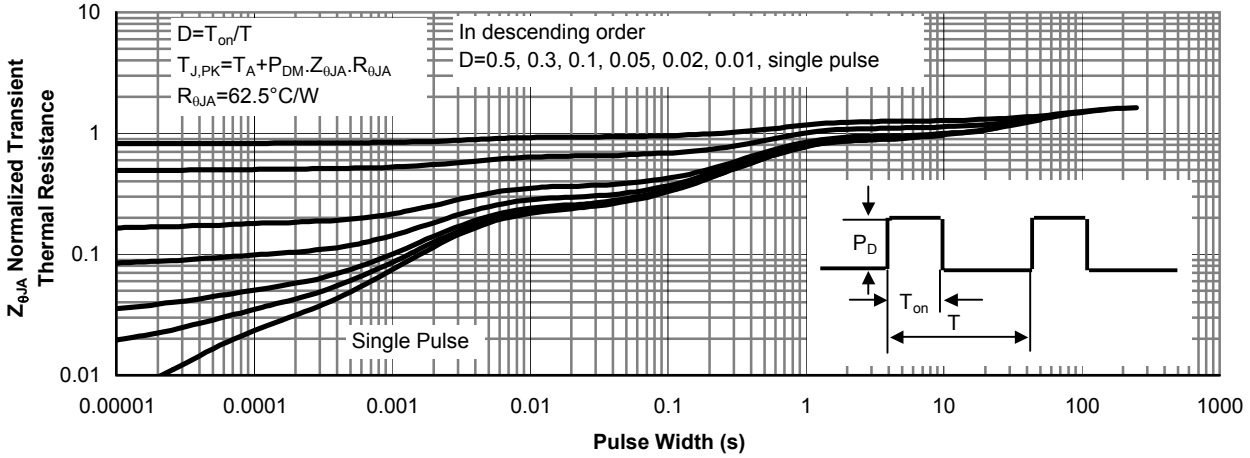


Figure 11: Normalized Maximum Transient Thermal Impedance

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS: SCHOTTKY

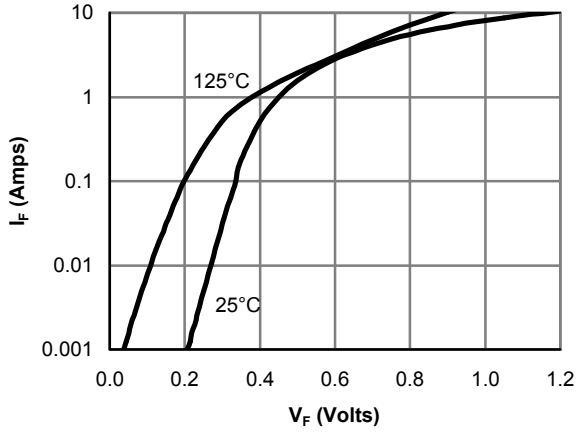


Figure 12: Schottky Forward Characteristics

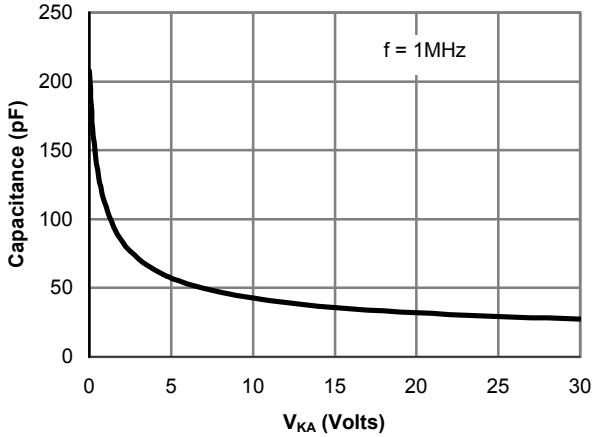


Figure 13: Schottky Capacitance Characteristics

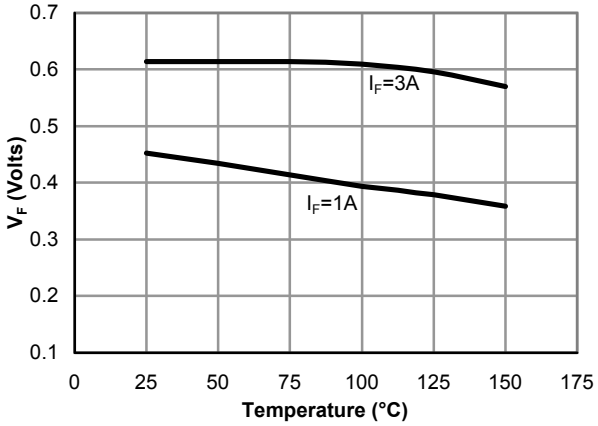


Figure 14: Schottky Forward Drop vs. Junction Temperature

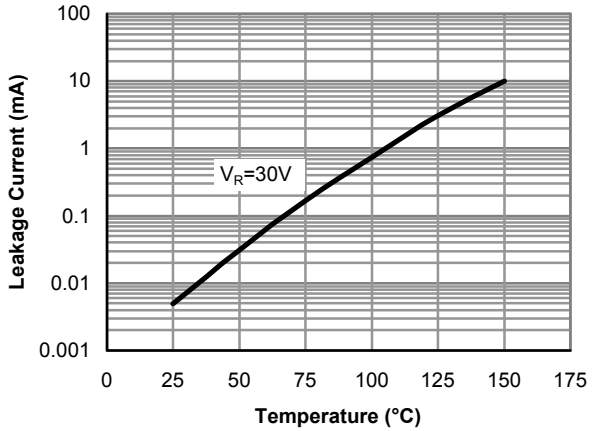


Figure 15: Schottky Leakage current vs. Junction Temperature

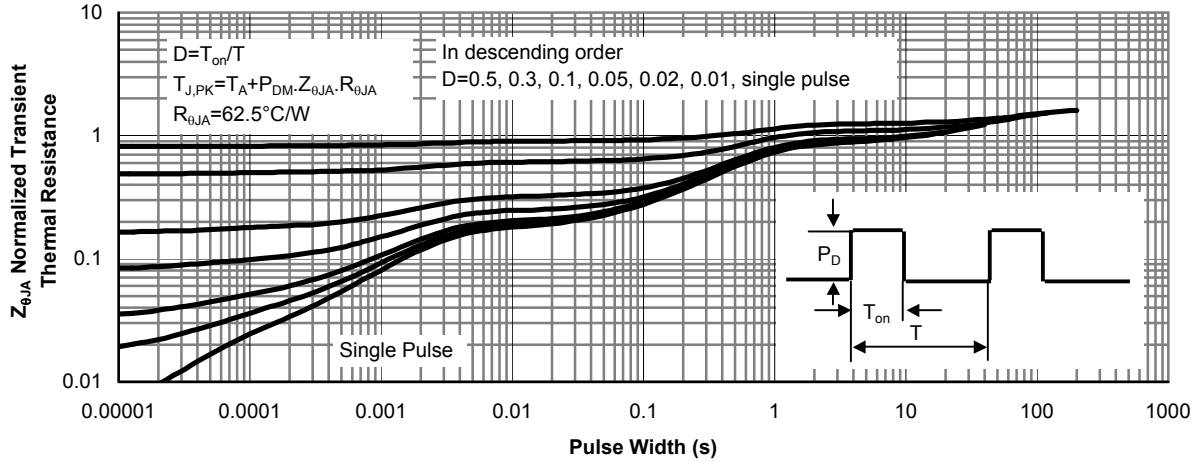
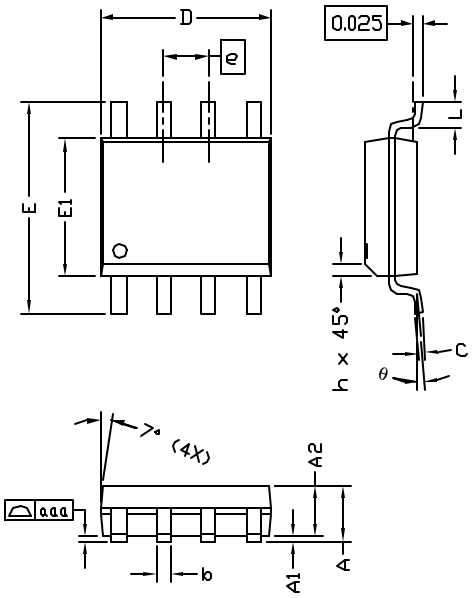


Figure 15: Schottky Normalized Maximum Transient Thermal Impedance

ALPHA & OMEGA
SEMICONDUCTOR, INC.

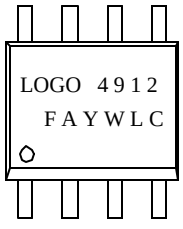
SO-8 Package Data



SYMBOLS	DIMENSIONS IN MILLIMETERS			DIMENSIONS IN INCHES		
	MIN	NOM	MAX	MIN	NOM	MAX
A	1.45	1.50	1.55	0.057	0.059	0.061
A1	0.00	——	0.10	0.000	——	0.004
A2	——	1.45	——	——	0.057	——
b	0.33	——	0.51	0.013	——	0.020
c	0.19	——	0.25	0.007	——	0.010
D	4.80	——	5.00	0.189	——	0.197
E1	3.80	——	4.00	0.150	——	0.157
e	1.27 BSC			0.050 BSC		
E	5.80	——	6.20	0.228	——	0.244
h	0.25	——	0.50	0.010	——	0.020
L	0.40	——	1.27	0.016	——	0.050
aaa	——	——	0.10	——	——	0.004
θ	0°	——	8°	0°	——	8°

NOTE:
1. LEAD FINISH: 150 MICROINCHES (3.8 um) MIN. THICKNESS OF Tin/Lead (SOLDER) PLATED ON LEAD
2. TOLERANCE ±0.10 mm (4 mil) UNLESS OTHERWISE SPECIFIED
3. COPLANARITY : 0.10 mm
4. DIMENSION L IS MEASURED IN GAGE PLANE

PACKAGE MARKING DESCRIPTION

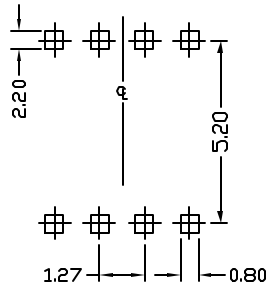


NOTE:
LOGO - AOS LOGO
4912 - PART NUMBER CODE.
F - FAB LOCATION
A - ASSEMBLY LOCATION
Y - YEAR CODE
W - WEEK CODE.
L C - ASSEMBLY LOT CODE

SO-8 PART NO. CODE

PART NO.	CODE
AO4912	4912

RECOMMENDED LAND PATTERN

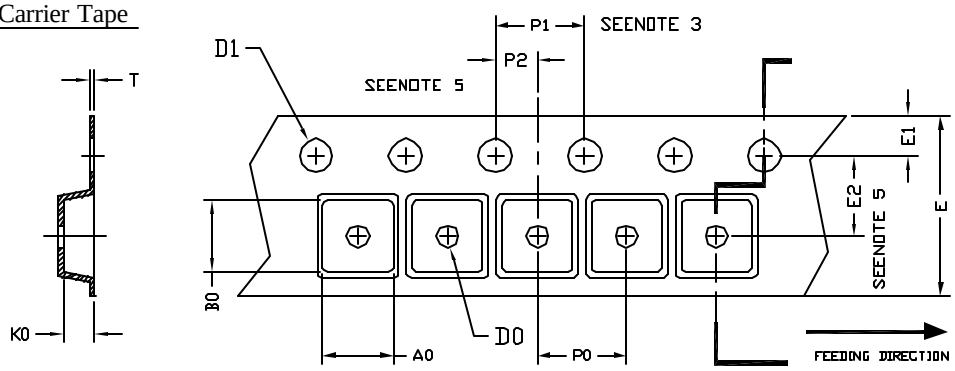


UNIT: mm

ALPHA & OMEGA
SEMICONDUCTOR, INC.

SO-8 Tape and Reel Data

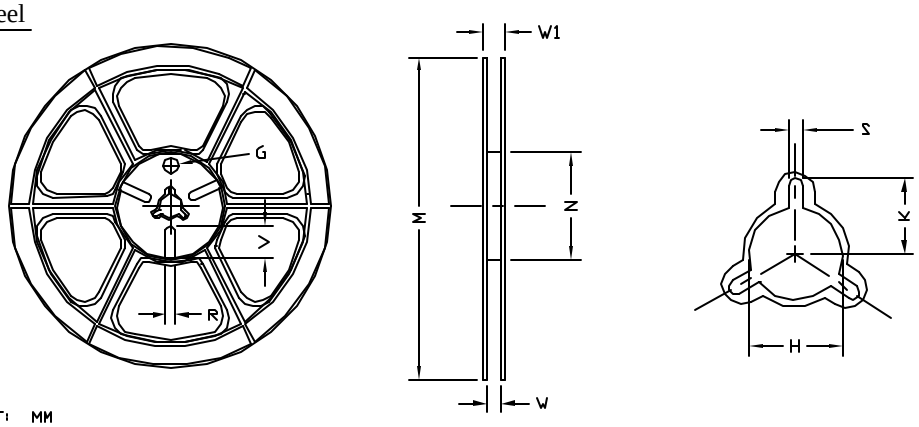
SO-8 Carrier Tape



UNIT: MM

PACKAGE	A0	B0	K0	D0	D1	E	E1	E2	P0	P1	P2	T
SO-8 (12 mm)	6.40 ±0.10	5.20 ±0.10	2.10 ±0.10	1.60 ±0.10	1.50 +0.10	12.00 ±0.30	1.75 ±0.10	5.50 ±0.05	8.00 ±0.10	4.00 ±0.10	2.00 ±0.05	0.25 ±0.05

SO-8 Reel



UNIT: MM

TAPE SIZE	REEL SIZE	M	N	W	W1	H	K	S	G	R	V
12 mm	ø330	ø330.00 ±0.50	ø97.00 ±0.10	13.00 ±0.30	17.40 ±1.00	ø13.00 +0.50 -0.20	10.60	2.00 ±0.50	---	---	---

SO-8 Tape

Leader / Trailer & Orientation